

Special Issue

Applications of Vision Measurement System on Product Quality Control

Message from the Guest Editor

Vision systems play a crucial role in industry, facilitating comprehensive quality assessment of product parameters through control and measurement tasks. They're integrated into quality assurance and management systems across the production line, offering data on products and processes. However, these systems face challenges in measurement performance due to disturbances like vibrations, temperature changes, and lighting variations. Despite this, advancements in imaging methods, sensor arrays, optics, and measurement algorithms have been significant. This Special Issue seeks articles showcasing vision systems' applications in measurement tasks for product parameter control. The focus is on imaging methods, calibration, and quality verification in industrial conditions, highlighting the potential of image analysis in improving product quality and production efficiency. The goal is to share authors' scientific contributions, driving innovation in the evolving industrial landscape.

Keywords: vision system; image analysis; quality control

Guest Editor

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As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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